



CD54HC165, CD74HC165, CD54HCT165, CD74HCT165

JAJSN8D – FEBRUARY 1998 – REVISED NOVEMBER 2021

CDx4HC165/CDx4HCT165 ハイスピード CMOS ロジック、8 ビット、パラレル入力、シリアル出力、シフト・レジスタ

1 特長

- バッファ付き入力
- 非同期パラレル・ロード
- 相補出力
- ファンアウト (全温度範囲にわたって)
 - 標準出力: 10 の LSTTL 負荷
 - バス・ドライバ出力: 15 の LSTTL 負荷
- 広い動作温度範囲: -55°C ~ 125°C
- 平衡な伝搬遅延と遷移時間
- LSTTL ロジック IC に比べて消費電力を大幅削減
- HC タイプ
 - 2V ~ 6V で動作
 - 優れたノイズ耐性: $N_{IL} = V_{CC}$ の 30%, $N_{IH} = V_{CC}$ の 30% ($V_{CC} = 5V$ の場合)
- HCT タイプ
 - 4.5V ~ 5.5V で動作
 - LSTTL 入力ロジックと直接互換、 $V_{IL} = 0.8V$ (最大値)、 $V_{IH} = 2V$ (最小値)
 - CMOS 入力互換、 V_{OL} 、 V_{OH} で $I_L \leq 1\mu A$

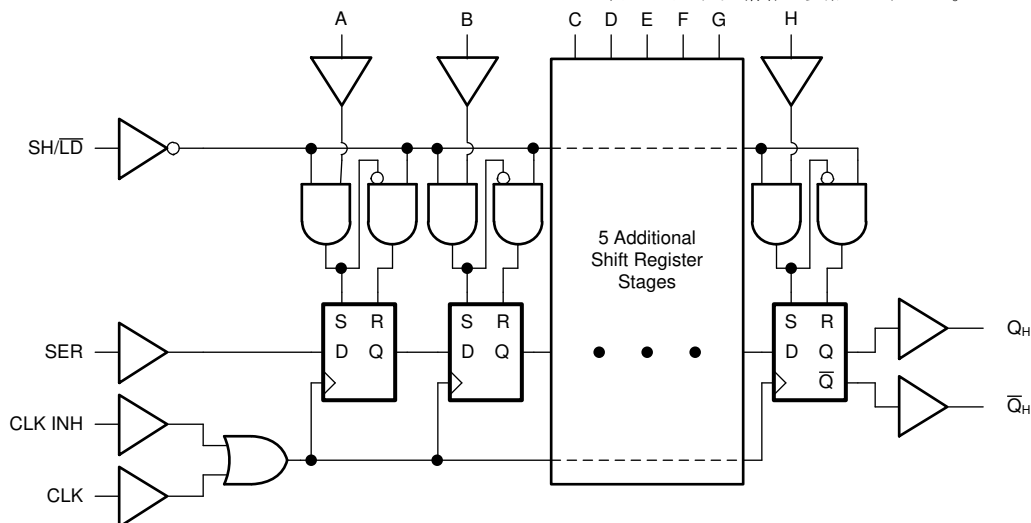
2 概要

'HC165 と 'HCT165 は、最終段から利用できる相補シリアル出力 (Q_H と $\bar{Q}_H$) を備えた 8 ビット・パラレルまたはシリアル入力シフト・レジスタです。パラレル・ロード (SH/LD) 入力が LOW の場合、A ~ H 入力のパラレル・データは非同期的にレジスタにロードされます。SH/LD が HIGH の場合、データは順次に SER 入力からレジスタに入り、クロックの立ち上がり遷移ごとに 1 つずつ右の位置 (A → B → C など) にシフトされます。この機能を使うと、 Q_H 出力を後続デバイスの SER 入力に接続することでパラレル入力シリアル出力コンバータを拡張できます。

製品情報

部品番号	パッケージ ⁽¹⁾	本体サイズ (公称)
CD54HC165F3A	CDIP (16)	24.38mm × 6.92mm
CD74HC165M	SOIC (16)	9.90mm × 3.90mm
CD74HC165E	PDIP (16)	19.31mm × 6.35mm
CD54HCT165F3A	CDIP (16)	24.38mm × 6.92mm
CD74HCT165M	SOIC (16)	9.90mm × 3.90mm
CD74HCT165E	PDIP (16)	19.31mm × 6.35mm

(1) 利用可能なすべてのパッケージについては、このデータシートの末尾にある注文情報を参照してください。



機能ダイアグラム



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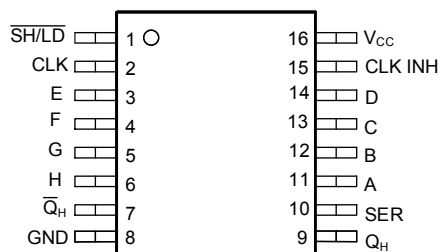
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3 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Changes from Revision C (October 2003) to Revision D (November 2021)	Page
• 最新のデータシート規格を反映するように、文書全体の表、図、相互参照の採番と書式設定を更新.....	1
• 現行の TI の命名規則に合わせてピン名を以下のように更新。PL を SH/LD、CP を CLK、D4 を E、D5 を F、D6 を G、D7 を H、 $\overline{Q}_7$ を $\overline{Q}_H$ 、Q ₇ を Q _H 、DS を SER、D0 を A、D1 を B、D2 を C、D3 を D、 $\overline{CE}$ を CLK INH。.....	1

4 Pin Configuration and Functions



J, N, or D package
16-Pin CDIP, PDIP, SOIC
Top View

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	Supply voltage		-0.5	7	V
I _{IK}	Input diode current	For V _I < -0.5 V or V _I > V _{CC} + 0.5 V		±20	mA
I _{OK}	Output diode current	For V _O < -0.5 V or V _O > V _{CC} + 0.5 V		±20	mA
I _O	Drain current per output	For V _O < -0.5 V or V _O > V _{CC} + 0.5 V		±25	mA
I _O	Output source or sink current per output pin	For V _O > -0.5 V or V _O < V _{CC} + 0.5 V		±25	mA
	Continuous current through V _{CC} or GND			±50	mA
T _J	Junction temperature			150	°C
T _{stg}	Storage temperature		-65	150	°C
	Lead temperature (Soldering 10s) (SOIC- Lead tips only)			300	°C

- (1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 Recommended Operating Conditions

			MIN	MAX	UNIT
V _{CC}	Supply voltage range	HC Types	2	6	V
		HCT Types	4.5	5.5	
V _I , V _O	Input or output voltage		0	V _{CC}	V
t _t	Input rise and fall time	2 V		1000	ns
		4.5 V		500	
		6 V		400	
T _A	Temperature range		-55	125	°C

5.3 Thermal Information

THERMAL METRIC		CD74HC165, CD74HCT165		UNIT
		D (SOIC)	N (PDIP)	
		16 PINS	16 PINS	
R _{θJA}	Junction-to-ambient thermal resistance ⁽¹⁾	73	67	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC package thermal metrics](#) application report.

5.4 Electrical Characteristics

PARAMETER		TEST CONDITIONS ⁽²⁾	V _{CC} (V)	25°C			-40°C to 85°C		-55°C to 125°C		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES											
V _{IH}	High level input voltage		2	1.5			1.5		1.5		V
			4.5	3.15			3.15		3.15		V
			6	4.2			4.2		4.2		V
V _{IL}	Low level input voltage		2	0.5			0.5		0.5		V
			4.5	1.35			1.35		1.35		V
			6	1.8			1.8		1.8		V
V _{OH}	High level output voltage	I _{OH} = – 20 µA	2	1.9			1.9		1.9		V
		I _{OH} = – 20 µA	4.5	4.4			4.4		4.4		V
		I _{OH} = – 20 µA	6	5.9			5.9		5.9		V
	High level output voltage	I _{OH} = – 4 mA	4.5	3.98			3.84		3.7		V
		I _{OH} = – 5.2 mA	6	5.48			5.34		5.2		V
V _{OL}	Low level output voltage	I _{OL} = 20 µA	2	0.1			0.1		0.1		V
		I _{OL} = 20 µA	4.5	0.1			0.1		0.1		V
		I _{OL} = 20 µA	6	0.1			0.1		0.1		V
	Low level output voltage	I _{OL} = 4 mA	4.5	0.26			0.33		0.4		V
		I _{OL} = 5.2 mA	6	0.26			0.33		0.4		V
I _I	Input leakage current	V _I = V _{CC} or GND	6	±0.1			±1		±1		µA
I _{CC}	Supply current	V _I = V _{CC} or GND	6	8			80		160		µA
HCT TYPES											
V _{IH}	High level input voltage		4.5 to 5.5	2			2		2		V
V _{IL}	Low level input voltage		4.5 to 5.5	0.8			0.8		0.8		V
V _{OH}	High level output voltage	I _{OH} = – 20 µA	4.5	4.4			4.4		4.4		V
	High level output voltage	I _{OH} = – 4 mA	4.5	3.98			3.84		3.7		V
V _{OL}	Low level output voltage	I _{OL} = 20 µA	4.5	0.1			0.1		0.1		V
	Low level output voltage	I _{OL} = 4 mA	4.5	0.26			0.33		0.4		V
I _I	Input leakage current	V _I = V _{CC} or GND	5.5	±0.1			±1		±1		µA
I _{CC}	Supply current	V _I = V _{CC} or GND	5.5	8			80		160		µA
ΔI _{CC} ⁽¹⁾	Additional quiescent device current per input pin	SER, A to H inputs held at V _{CC} – 2.1	4.5 to 5.5	100 126			157.5		171.5		µA
		CLK and SH/LD inputs held at V _{CC} – 2.1	4.5 to 5.5	100 234			292.5		318.5		

(1) For dual-supply systems theoretical worst case (V_I = 2.4 V, V_{CC} = 5.5 V) specification is 1.8 mA.

(2) V_I = V_{IH} or V_{IL}.

5.5 Prerequisite for Switching Characteristics

PARAMETER		V _{CC} (V)	25°C		-40°C to 85°C		-55°C to 125°C		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t _{WL} , t _{WH}	CLK Pulse Width	2	80		100		120		ns
		4.5	16		20		24		
		6	14		17		20		
t _{WL}	SH/ŁD Pulse Width	2	80		100		120		ns
		4.5	16		20		24		
		6	14		17		20		
t _{SU}	Set-up Time SER to CLK	2	80		100		120		ns
		4.5	16		20		24		
		6	14		17		20		
t _{SU(L)}	CLK INH to CLK	2	80		100		120		ns
		4.5	16		20		24		
		6	14		17		20		
t _{SU}	A-H to SH/ŁD	2	80		100		120		ns
		4.5	16		20		24		
		6	14		17		20		
t _H	Hold Time SER to CLK or CLK INH	2	35		45		55		ns
		4.5	7		9		11		
		6	6		8		9		
t _H	CLK INH to CLK	2	0		0		0		ns
		4.5	0		0		0		
		6	0		0		0		
t _{REC}	Recovery Time SH/ŁD to CLK	2	100		125		150		ns
		4.5	20		25		30		
		6	17		21		26		
f _{MAX}	Maximum Clock Pulse Frequency	2	6		5		4		MHz
		4.5	30		24		20		
		6	35		28		24		
HCT TYPES									
t _{WL} , t _{WH}	CLK Pulse Width	4.5	18		23		27		ns
t _{WL}	SH/ŁD Pulse Width	4.5	20		25		30		ns
t _{SU}	Set-up Time SER to CLK	4.5	20		25		30		ns
t _{SU(L)}	CLK INH to CLK	4.5	20		25		30		ns
t _{SU}	A-H to SH/ŁD	6	20		25		30		ns
t _H	Hold Time SER to CLK or CLK INH	4.5	7		9		11		ns
t _S , t _H	CLK INH to CLK	4.5	0		0		0		ns
t _{REC}	Recovery Time SH/ŁD to CLK	4.5	20		25		30		ns
f _{MAX}	Maximum Clock Pulse Frequency	4.5	27		22		18		MHz

5.6 Switching Characteristics

Input t_r , t_f = 6 ns. Unless otherwise specified, C_L = 50pF

PARAMETER		V _{CC} (V)	25°C		-40°C to 85°C	-55°C to 125°C	UNIT
			TYP	MAX	MAX	MAX	
HC TYPES							
t _{pd}	CLK or CLK INH to Q _H or $\overline{Q}_H$	2		165	205	250	ns
		4.5	13 ⁽³⁾	33	41	50	ns
		6		28	35	43	ns
	SH/ $\overline{LD}$ to Q _H or $\overline{Q}_H$	2		175	220	265	ns
		4.5	14 ⁽³⁾	35	44	53	ns
		6		30	37	45	ns
	H to Q _H or $\overline{Q}_H$	2		150	190	225	ns
		4.5	12 ⁽³⁾	30	38	45	ns
		6		26	33	38	ns
t _t	Output Transition Times	2		75	95	110	ns
		4.5		15	19	22	ns
		6		13	16	19	ns
C _{IN}	Input Capacitance			10	10	10	pF
C _{PD}	Power Dissipation Capacitance ^{(1) (2)}	5	17				pF
HCT TYPES							
t _{pd}	CLK or CLK INH to Q _H or $\overline{Q}_H$	4.5	17 ⁽³⁾	40	50	60	ns
	SH/ $\overline{LD}$ to Q _H or $\overline{Q}_H$	4.5	17 ⁽³⁾	40	50	60	ns
	H to Q _H or $\overline{Q}_H$	4.5	14 ⁽³⁾	35	44	53	ns
t _t	Output Transition Times	4.5		15	19	22	ns
C _{IN}	Input Capacitance			10	10	10	pF
C _{PD}	Power Dissipation Capacitance ^{(1) (2)}	5	24				pF

(1) C_{PD} is used to determine the dynamic power consumption, per package.

(2) $P_D = V_{CC}^2 f_i + \Sigma (C_L V_{CC}^2 + f_o)$ where f_i = Input Frequency, f_o = Output Frequency, C_L = Output Load Capacitance, V_{CC} = Supply Voltage.

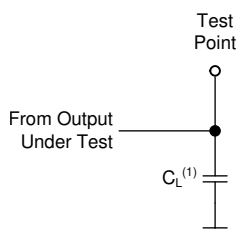
(3) C_L = 15 pF and V_{CC} = 5 V.

6 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1 \text{ MHz}$, $Z_O = 50 \Omega$, $t_f < 6 \text{ ns}$.

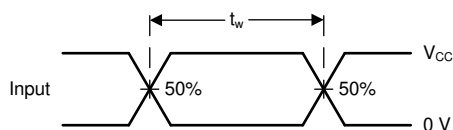
For clock inputs, $f_{\max}$ is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.

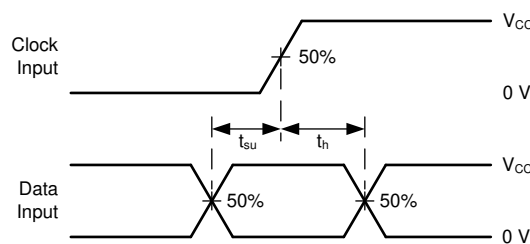


(1) C_L includes probe and test-fixture capacitance.

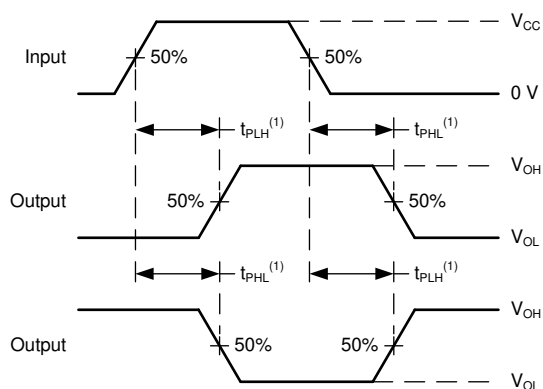
FIG 6-1. Load Circuit for Push-Pull Outputs



**FIG 6-2. Voltage Waveforms, Standard CMOS Inputs
Pulse Duration**

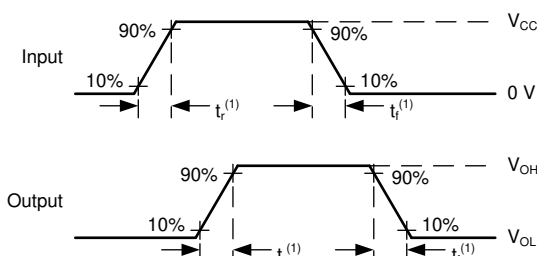


**FIG 6-3. Voltage Waveforms, Standard CMOS Inputs
Setup and Hold Times**



(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .

**FIG 6-4. Voltage Waveforms, Standard CMOS Inputs
Setup Propagation Delays**

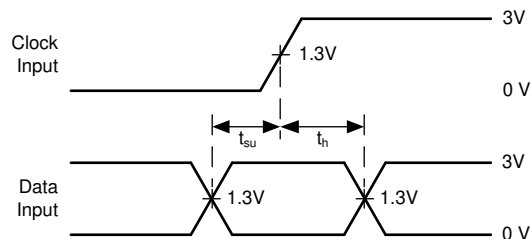


(1) The greater between t_r and t_f is the same as t_t .

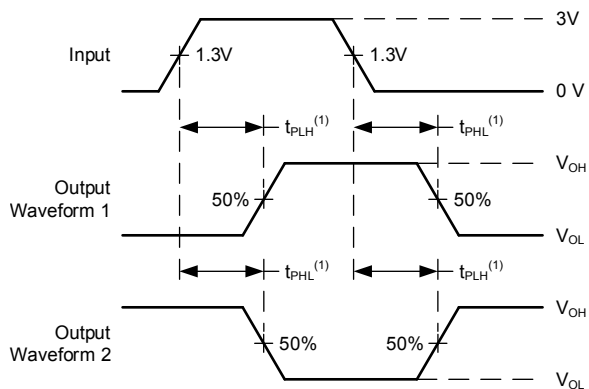
**FIG 6-5. Voltage Waveforms, Input and Output
Transition Times for Standard CMOS Input Devices**



6-6. Voltage Waveforms, TTL-Compatible CMOS Inputs Pulse Duration



6-7. Voltage Waveforms, TTL-Compatible CMOS Inputs Setup and Hold Times



(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .

6-8. Voltage Waveforms, TTL-Compatible CMOS Inputs Propagation Delays

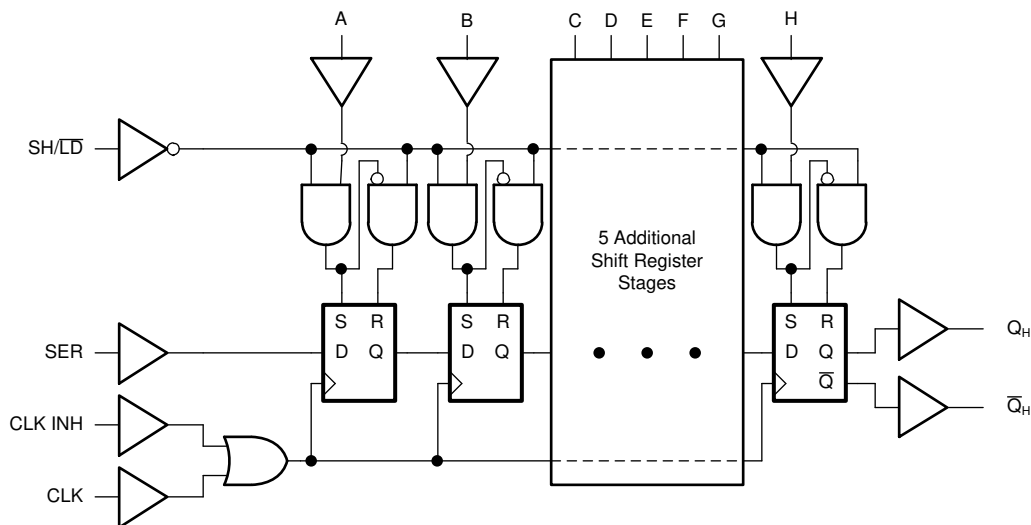
7 Detailed Description

7.1 Overview

The 'HC165 and 'HCT165 are 8-bit parallel or serial-in shift registers with complementary serial outputs (Q_H and $\bar{Q}_H$) available from the last stage. When the parallel load ($SH/\bar{LD}$) input is LOW, parallel data from the A to H inputs are loaded into the register asynchronously. When the $SH/\bar{LD}$ is HIGH, data enters the register serially at the SER input and shifts one place to the right ($A \rightarrow B \rightarrow C$, etc.) with each positive-going clock transition. This feature allows parallel-to-serial converter expansion by connecting the Q_H output to the SER input of the succeeding device.

For predictable operation the LOW-to-HIGH transition of CLK INH should only take place while CLK is HIGH. Also, CLK and CLK INH should be LOW before the LOW-to-HIGH transition of $SH/\bar{LD}$ to prevent shifting the data when $SH/\bar{LD}$ goes HIGH.

7.2 Functional Block Diagram



7.3 Device Functional Modes

表 7-1. Truth Table⁽¹⁾

OPERATING MODE	INPUTS					QnREGISTER		OUTPUTS	
	SHLD	CLK INH	CLK	SER	A - H	Q _A	Q _B - Q _G	Q _H	$\bar{Q}_H$
Parallel Load	L	X	X	X	L	L	L-L	L	H
	L	X	X	X	H	H	H-H	H	L
Serial Shift	H	L	↑	l	X	L	q _A - q _F	q _G	$\bar{q}_G$
	H	L	↑	h	X	H	q _A - q _F	q _G	$\bar{q}_G$
Hold (Do Nothing)	H	H	X	X	X	q _A	q _B - q _G	q _H	$\bar{q}_H$

- (1) H = High voltage level.
h = High voltage level one set-up time prior to the low-to-high clock transition.
l = Low voltage level one set-up time prior to the low-to-high clock transition.
L = Low voltage level.
X = Don't care.
↑ = Transition from low to high level.
q_n = Lower case letters indicate the state of the reference output clock transition.

8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

9 Layout

9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.2 サポート・リソース

TI E2E™ サポート・フォーラムは、エンジニアが検証済みの回答と設計に関するヒントをエキスパートから迅速かつ直接得ることができる場所です。既存の回答を検索したり、独自の質問をしたりすることで、設計に必要な支援を迅速に得ることができます。

リンクされているコンテンツは、該当する貢献者により、現状のまま提供されるものです。これらは TI の仕様を構成するものではなく、必ずしも TI の見解を反映したものではありません。TI の[使用条件](#)を参照してください。

10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

すべての商標は、それぞれの所有者に帰属します。

10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
5962-8685501EA	Active	Production	CDIP (J) 16	25 TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-8685501EA CD54HCT165F3A
CD54HC165F3A	Active	Production	CDIP (J) 16	25 TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8409501EA CD54HC165F3A
CD54HC165F3A.A	Active	Production	CDIP (J) 16	25 TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	8409501EA CD54HC165F3A
CD54HCT165F3A	Active	Production	CDIP (J) 16	25 TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-8685501EA CD54HCT165F3A
CD54HCT165F3A.A	Active	Production	CDIP (J) 16	25 TUBE	No	SNPB	N/A for Pkg Type	-55 to 125	5962-8685501EA CD54HCT165F3A
CD74HC165E	Active	Production	PDIP (N) 16	25 TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74HC165E
CD74HC165E.A	Active	Production	PDIP (N) 16	25 TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74HC165E
CD74HC165M	Obsolete	Production	SOIC (D) 16	-	-	Call TI	Call TI	-55 to 125	HC165M
CD74HC165M96	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU SN	Level-1-260C-UNLIM	-55 to 125	HC165M
CD74HC165M96.A	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC165M
CD74HC165MT	Obsolete	Production	SOIC (D) 16	-	-	Call TI	Call TI	-55 to 125	HC165M
CD74HCT165E	Active	Production	PDIP (N) 16	25 TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74HCT165E
CD74HCT165E.A	Active	Production	PDIP (N) 16	25 TUBE	Yes	NIPDAU	N/A for Pkg Type	-55 to 125	CD74HCT165E
CD74HCT165M	Obsolete	Production	SOIC (D) 16	-	-	Call TI	Call TI	-55 to 125	HCT165M
CD74HCT165M96	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU SN	Level-1-260C-UNLIM	-55 to 125	HCT165M
CD74HCT165M96.A	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT165M
CD74HCT165M96G4	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT165M
CD74HCT165M96G4.A	Active	Production	SOIC (D) 16	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT165M

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

(4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF CD54HC165, CD54HCT165, CD74HC165, CD74HCT165 :

- Catalog : [CD74HC165](#), [CD74HCT165](#)
- Military : [CD54HC165](#), [CD54HCT165](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Military - QML certified for Military and Defense Applications

TAPE AND REEL INFORMATION



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC165M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HC165M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HCT165M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HCT165M96G4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC165M96	SOIC	D	16	2500	340.5	336.1	32.0
CD74HC165M96	SOIC	D	16	2500	340.5	336.1	32.0
CD74HCT165M96	SOIC	D	16	2500	353.0	353.0	32.0
CD74HCT165M96G4	SOIC	D	16	2500	353.0	353.0	32.0

TUBE

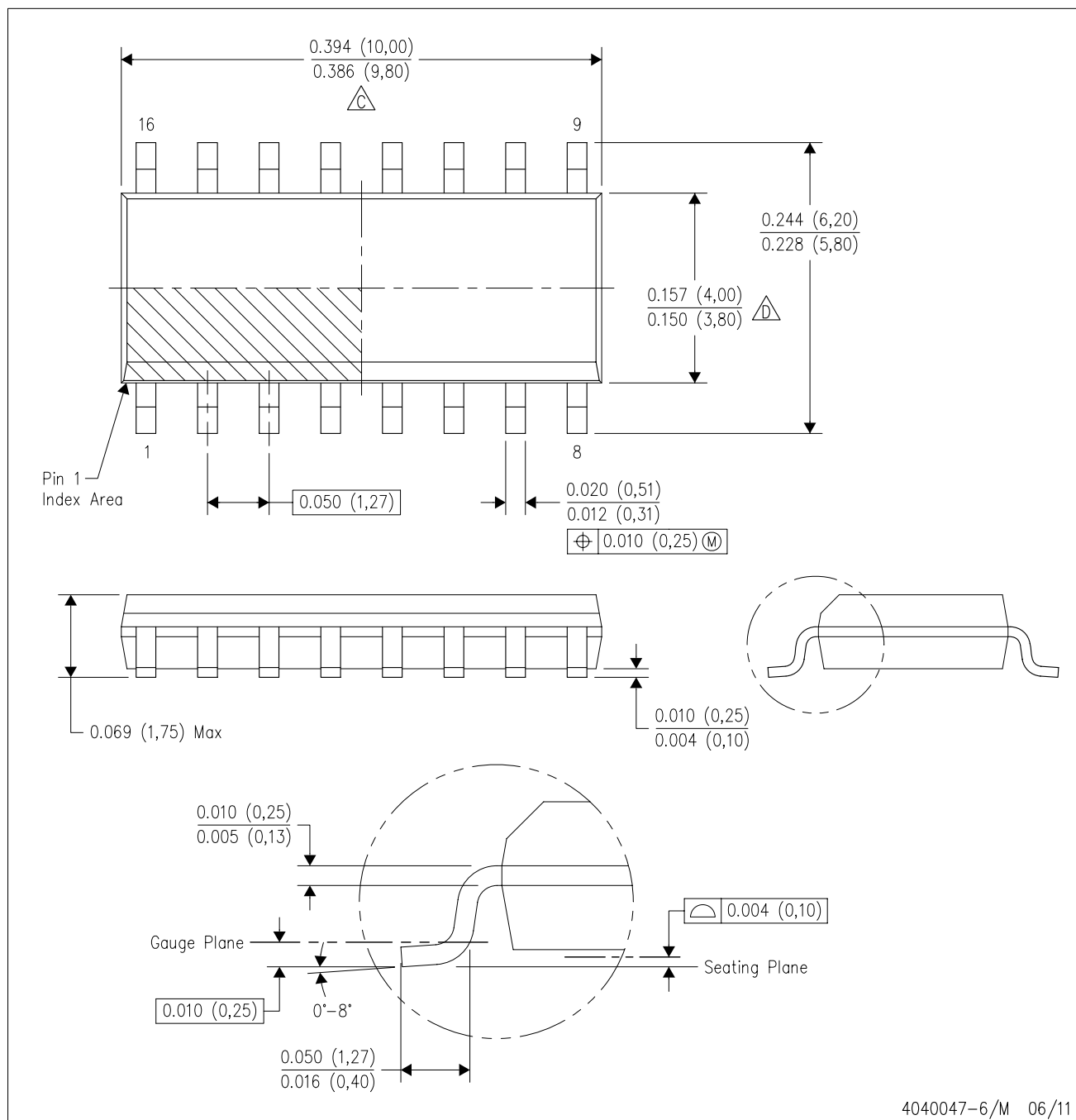


*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
CD74HC165E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HC165E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HC165E.A	N	PDIP	16	25	506	13.97	11230	4.32
CD74HC165E.A	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT165E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT165E	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT165E.A	N	PDIP	16	25	506	13.97	11230	4.32
CD74HCT165E.A	N	PDIP	16	25	506	13.97	11230	4.32

D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- D. Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.

J (R-GDIP-T**)

14 LEADS SHOWN

CERAMIC DUAL IN-LINE PACKAGE



PINS ** DIM	14	16	18	20
A	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC	0.300 (7,62) BSC
B MAX	0.785 (19,94)	.840 (21,34)	0.960 (24,38)	1.060 (26,92)
B MIN	—	—	—	—
C MAX	0.300 (7,62)	0.300 (7,62)	0.310 (7,87)	0.300 (7,62)
C MIN	0.245 (6,22)	0.245 (6,22)	0.220 (5,59)	0.245 (6,22)



4040083/F 03/03

- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - C. This package is hermetically sealed with a ceramic lid using glass frit.
 - D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
 - E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

16 PINS SHOWN

PLASTIC DUAL-IN-LINE PACKAGE



PINS ** DIM	14	16	18	20
A MAX	0.775 (19,69)	0.775 (19,69)	0.920 (23,37)	1.060 (26,92)
A MIN	0.745 (18,92)	0.745 (18,92)	0.850 (21,59)	0.940 (23,88)
MS-001 VARIATION	AA	BB	AC	AD



4040049/E 12/2002

- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 -  Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
 -  The 20 pin end lead shoulder width is a vendor option, either half or full width.

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